



## List of posters

PA-1	In situ piezoelectric studies of PZT thin films by X-Ray microdiffraction	Cornelius, T.	255
PA-2	Effect of indentation induced strain on epitaxial Fe layers	Tholapi, R.	256
PA-3	Structure and Morphology of Thin Films of a BTBT Derivative: A Combined X-ray Reflectivity and AFM Study	Jones, A.	257
PA-4	Structural Properties of Picene-Perfluoropentacene and Picene-Pentacene Blends: Superlattice Formation versus Limited Intermixing	Gerlach, A.	258
PA-5	In-situ X-ray diffraction annealing study on an anthradithiophene derivative	Rozbořil, J.	258
PA-6	X-ray analysis of strained epitaxial layers in skew geometry	Zaumseil, P.	259
PA-7	In-situ X-ray analysis of Nickel silicide formation	Zaumseil, P.	260
PA-8	X-ray analysis of thermal strain release in Ge patches on Si pillars	Zaumseil, P.	261
PA-9	Time-resolved in-situ X-ray investigations during growth of $\text{In}_x\text{Ga}_{1-x}\text{As}$ core-shell nanowire structures	Feigl, L.	262
PA-10	In-situ time-resolved XRD and RHEED study of the polytypism in GaAs nanowires	Jakob, J.	263
PA-11	Grazing-incidence X-ray characterization of semiconductor nanowires	Gokhale, M	264
PA-12	Si/GaP core-shell nanowires: towards direct band-gap group IV semiconductors	Stangl, J.	265
PA-13	Thermal annealing and growth of a single GaAs nanowire studied by in-situ time-resolved x-ray diffraction	Mostafavi Kashani, S.	265
PA-14	Analyse the electron and spin density profiles of a multilayer structures using wavelet transform analysis of X-ray reflectivity data	Ksenzov, D.	266
PA-15	X-ray dynamical diffraction in non-periodic layered materials with large d-spacing: application to $\text{Bi}_2\text{Te}_3$ films grown on BaF <sub>2</sub> (111)	Morelhão, S. L.	267
PA-16	X-ray diffraction study of topological insulator epitaxial thin films	Caha, O.	268
PA-17	Visualization of inhomogeneous layers and interfaces in ultra thin films by X-ray reflectivity	Jiang, J.	269
PA-18	Structure of self-organized periodic silver dichromate rings in ultra thin film	Jiang, J.	270
PA-19	Fast and Accurate solution for in-line monitoring of strain field through High Resolution X-Ray Diffraction Reciprocal Space Mapping	Durand, A.	271
PA-20	From Periodic to Ordered Non-Periodic Nanostructures: GISAXS on Nanoimprinted Quasicrystals	Pflüger, M.	272
PA-21	Grazing Incidence X-Ray Small Angle Scattering for Determining Shape of Semiconductor Device Patterns	Omote, K.	273
PA-22	Characterization of sub-nanometer Cr/Sc multilayer systems for the water window	Haase, A.	275
PA-23	Misfit dislocation density determination at relaxation onset: reciprocal space map analysis of thin SiGe/Si layers	Benediktovich, A.	275
PA-24	The microstructure of Si surface layers after He <sup>+</sup> plasma immersion ion implantation and subsequent annealing	Shcherbachev, K.	276
PA-25	In-situ GISAXS investigation of thermal and solvent annealing of high- block copolymers	Buttard, D.	277
PA-26	Distinct palm-like diffuse sheets from lamellar gratings studied with small angle soft X-ray scattering	Fernandez-Herrero, A.	278
PA-27	In-situ synchrotron studies of dendrite growth in solidifying Ga-In alloys	Grenzer, J.	279
PA-28	Structural changes across the metal-insulator transition in thin epitaxial VO <sub>2</sub> films	Grenzer, J.	280
PA-29	Incorporation of interfacial roughness to recursion matrix formalism of dynamical x-ray diffraction in multilayers and superlattices	Lobach, I.	281
PA-30	Structure of superconducting MgB <sub>2</sub> thin films annealed in oxygen	Roch, T.	282
PA-31	Numerical modelling of reflective multilayer based X-ray optics	Piault, P.	283



PA-32	Characterization of titanium and titanium (IV) oxide nanofilms with x-ray reflectometry and grazing incident x-ray diffraction	Stabrawa, I.	284
PA-33	Full strain tensor determination in synthesized diamonds and diamonds films	Borcha, M.	285
PA-34	Structure diagnostics of heterostructures and multilayered system by X-ray multiple diffraction	Borcha, M.	286
PA-35	Defect structure of high-resistant CdTe crystals studied by high-resolution X-ray diffraction	Fodchuk, I.	286
PA-36	Defect and magnetic structure of $Y_{2.95}La_{0.05}Fe_5O_{12}/Gd_3Ga_5O_{12}$ epitaxial systems	Fodchuk, I.	287
PA-37	X-Ray Reflectometry and scattering study of the surface nanolayers on colloidal silica	Roshchin, B. S.	288
PA-38	Synthesis, crystal structure studies and validation using X-ray powder diffraction combined with DFT calculations of bioactive derivatives.	Shalaby ElSayed, M.	289
PA-39	X-ray diffraction studies of cubic GaN epilayers grown on 3C-SiC/Si	Frentrup, M.	290
PA-40	Relaxation of a large amount of Local Strain in Protein Crystals by using Seed Crystals	Lazarev, S.	290
PA-41	Ultrafast melting of polystyrene colloidal crystals investigated in pump-probe experiments at x-ray free electron laser	Lazarev, S.	291
PB-1	The influence of Y and Ce ions to changes of crystal structure of zirconia oxides	Turchenko, V. A.	292
PB-2	Influence of high pressure and temperature on crystal structure of double perovskites	Turchenko, V. A.	294
PB-3	The refinement of atomic and magnetic structure of $BaFe_{12-x}In_xO_{19}$ ( $x=0.1-1.2$ ) by neutron diffraction	Turchenko, V. A.	295
PB-4	Structure study of the shape memory alloy $Ni_2MnGa$ doped with In	Cejpek, P.	297
PB-5	Omega phase particles in Ti – 8.1 at.% Mo alloy studied by anomalous x-ray diffraction	Šmilauerová, J.	297
PB-6	Structure determination of a complex zeolite by combining rotation electron diffraction, HRTEM and PXRD	Cichočka, M.	297
PB-7	XRD and TEM characterization of polar GaN layers grown by HTVPE on sapphire substrates	Barchuk, M.	299
PB-8	Behavior of 2-mercaptobenzimidazole under high-pressure conditions	Tomkowiak, H.	300
PB-9	High pressure study of 3-hydroxy-4,5-dimethyl-1-phenylpyridazin-6-one	Rozsak, K.	301
PB-10	Skew asymmetric arrangement of X-ray diffraction for structural diagnostics of multi-layer semiconductor materials	Fodchuk, I.	301
PB-11	Long-range interaction of residual deformation fields in the X-ray triple-crystalline LLL-interferometer	Fodchuk, I.	302
PB-12	Study of single dislocations by topo-tomography with X-ray laboratory set-up	Zolotov, D.	303
PB-13	Quantitative synchrotron topography application for crystals of grooved Si and Zn- $GeP_2$	Podurets, K.	304
PB-14	Imaging and Density Estimation of Icy Materials under temperature-controlled conditions using Phase Contrast X-ray Computed Tomography	Takeya, S.	304
PB-15	Phase contrast tomographic imaging of polymer composites	Kalasová, D.	304
PB-16	Optimization of channel-cut X-ray optics for high-throughput and high-resolution laboratory small-angle X-ray scattering experiments	Nadazdy, P.	306
PB-17	Performing high-resolution in-plane Bragg surface diffraction using multiple-beam diffraction	Huang, X.	306
PB-18	Highly efficient and tuneable silicon diffractive lenses for hard X-ray microdiffraction experiments	Lebugle, M.	307
PB-19	Complete characterisation of reflection grating properties by atomic force microscopy (AFM), X-ray diffraction (XRD) and grazing incidence X-ray fluorescence analysis (GIXRF)	Jark, W.	308



PB-20	Multilayer Laue Lens fabrication at Fraunhofer IWS Dresden	Kubec, A.	309
PB-21	Achieving point and line focus using Multilayer Laue Lenses at ESRF beamline ID13	Kubec, A.	309
PB-22	Non-scanning X-ray fluorescence spectromicroscopy with a laboratory X-ray source	Sakurai, K.	310
PB-23	Structure Analysis of Drug Delivery Systems with SAXS in the Laboratory	Puhr, B.	311
PB-24	First tests of X-ray imaging using pixel detectors base on semi-insulating GaAs	Za ko, B.	312
PB-25	The X-Ray Bi- and Multichromator – Theory and Alignment	Hrdý, J.	313
PB-26	High-quality active surfaces for X-ray crystal optics	Zápražný, Z.	313
PB-27	An automatic sample positioning system for nano-beam X-ray diffraction multi-scale mapping	Imai, Y.	314
PB-28	Recent progress in design and technology of channel-cut monochromators	Korytár, D.	315
PB-29	High-resolution Micro- and Nano-beam Diffraction System at BL13XU of the SPring-8	Kimura, S.	317
PB-30	DanMAX – The Danish beamline for in situ materials studies at MAX IV	Kantor, I.	317
PB-31	Biomedical imaging at Max IV	Mokso, P.	318
PB-32	Automated, efficient and high-throughput data acquisition at the ESRF bioSAXS beamline BM29	Pernot, .P.	318
PB-33	The TOMCAT hard X-ray full field TXM	Bonnin, A.	320
PB-34	Simulation of resolution effects in HRXRD by semi-analytical ray-tracing	Mikhalychev, A.	320
PB-35	Complementary data from photoemission in hard x-ray reflection experiments	Stoupin, S.	321
PB-36	DTXRD - collection of software tools for evaluation of single crystals using x-ray diffraction	Stoupin, S.	322
PB-37	Coherent Diffraction based Imaging at the Diamond Light Source by utilising I13's unique Coherence Properties	Wagner, U.	322
PB-38	Diamond Manchester beamline (I13-Imaging) at Diamond Light Source (DLS) – New Developments	Cipiccia, S.	323
PB-39	High precision X-ray multilayer mirrors for customized solutions	Niese, S.	324
PB-40	Structural studies of the growth and orientation of M- and Y-type ferrites prepared by chemical solution deposition method	Dopita, M.	324